

Features

- 125-MSPS Update Rate
- 10-bit Resolution
- Differential Current Outputs: 2 mA to 20 mA
- SFDR at 100-MHz Clock with 1-MHz Output: 64 dBc
- Fast Settling: 35-ns Full-Scale Settling to 0.1%
- On-Chip 1.10-V Reference
- Edge-Triggered Latches
- Power Dissipation: 115 mW @ 5 V
- Single +5-V or +3-V Supply Operation
- Green, TSSOP28 Package

Applications

- Communications Transmit Channel
- Signal Reconstruction
- Direct Digital Synthesis (DDS)
- Instrumentation
- Video Reconstruction

Highlights

- Manufactured on a CMOS process, the 3PD5651E uses a proprietary switching technique that enhances dynamic performance well beyond 8- and 10-bit video DACs.
- The on-chip, edge-triggered input CMOS latches readily interface to +3-V and +5-V CMOS logic families. The 3PD5651E can support update rates up to 125 MSPS.
- A flexible single-supply operating range of +2.7 V to +5.5 V and a wide full-scale current adjustment span of 2 mA to 20 mA allows the 3PD5651E to operate at reduced power levels (i.e., 45 mW) without any degradation in dynamic performance.
- A temperature compensated, 1.10-V bandgap reference is included on-chip providing a complete DAC solution. An external reference may be used.
- The current output(s) of the 3PD5651E can easily be configured for various single-ended or differential applications.

Description

The 3PD5651E offers exceptional AC and DC performance while supporting update rates up to 125 MSPS. The flexible single-supply operating range from +2.7 V to +5.5 V and the low power dissipation of the 3PD5651E are well suited for portable and low power applications. Its power dissipation can be further reduced to 45 mW, without a significant degradation in performance, by lowering the full-scale current output. In addition, a power-down mode reduces the standby power dissipation to approximately 20 mW.

The 3PD5651E is manufactured on an advanced CMOS process. A segmented current source architecture is combined with a proprietary switching technique to reduce spurious components and enhance dynamic performance. The edge-triggered input latches and a temperature compensated bandgap reference have been integrated to provide a complete monolithic DAC solution. Flexible supply options support +3-V and +5-V CMOS logic families.

The 3PD5651E is a current-output DAC with a nominal full-scale output current of 20 mA and an output impedance of > 100 k Ω .

Differential current outputs are provided to support single-ended or differential applications. The current outputs may be directly tied to an output resistor to provide two complementary, single-ended voltage outputs. The output voltage compliance range is 1.25 V.

The 3PD5651E contains a 1.10-V on-chip reference and reference control amplifier, which allows the full-scale output current to be simply set by a single resistor. The 3PD5651E can be driven by a variety of external reference voltages.

The full-scale current of the 3PD5651E can be adjusted over a 2-mA to 20-mA range without any degradation in dynamic performance. Thus, the 3PD5651E may operate at reduced power levels or be adjusted over a 20-dB range to provide additional gain ranging capabilities.

The 3PD5651E is available in the TSSOP28 package. It is specified for the operation over the industrial temperature range.

Functional Block Diagram

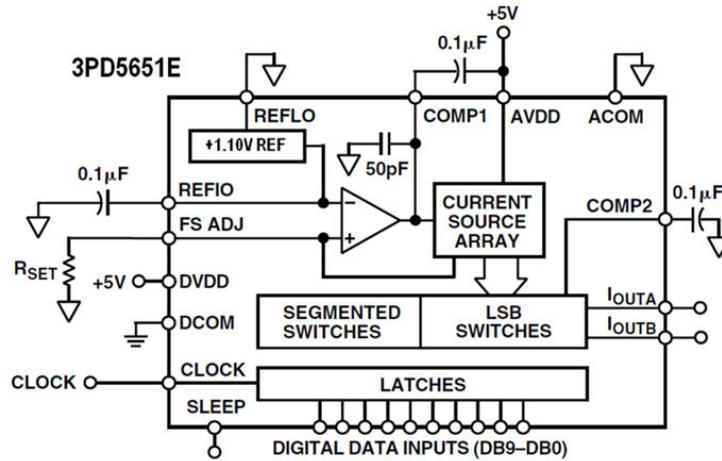


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Revision History

Date	Revision	Notes
2011-01-15	Rev.A.0	Initial release.
2025-10-11	Rev.A.1	Updated to a new datasheet format. Added the Tape and Reel Information. Updated the Package Outline Dimensions.

Pin Configuration and Functions

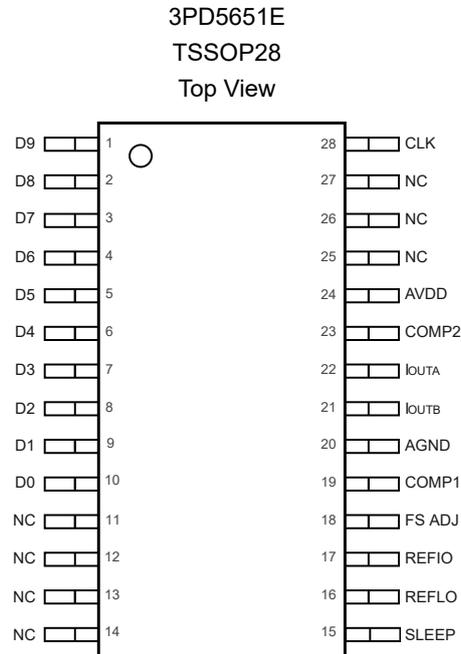


Table 1. Pin Functions

Pin No.	Name	Description
1	DB9	The most significant data bit (MSB).
2–9	DB8–DB1	Data bits 1–8.
10	DB0	The least significant data bit (LSB).
11–14,25	NC	No internal connection.
15	SLEEP	The power-down control input. Active high. It contains the active pull-down circuit, and thus it may be left unterminated if not used.
16	REFLO	The reference ground when the internal 1.10-V reference is used. Connected to AVDD to disable the internal reference.
17	REFIO	The reference input/output. It serves as the reference input when the internal reference is disabled (i.e., tie REFLO to AVDD). It serves as a 1.10-V reference output when the internal reference is activated (i.e., tie REFLO to ACOM). It requires a 0.1-mF capacitor to ACOM when the internal reference is activated.
18	FS ADJ	The full-scale current output adjust.
19	COMP1	The bandwidth/noise reduction node. Add 0.1 mF to AVDD for optimum performance.
20	ACOM	The analog common.
21	I _{OUTB}	The complementary DAC current output. It is a full-scale current when all data bits are 0 s.
22	I _{OUTA}	The DAC current output. It is a full-scale current when all data bits are 1 s.
23	COMP2	The internal bias node for switch driver circuitry. It must decouple to ACOM with a 0.1-mF capacitor or larger.
24	AVDD	The analog supply voltage (+2.7 V to +5.5 V).

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Pin No.	Name	Description
25	NC	Not connected.
26	NC	Not connected.
27	NC	Not connected.
28	CLK	The clock input. The data is latched on the positive edge of the clock of the 3PD5651E.

Specifications

Absolute Maximum Ratings ⁽¹⁾

Parameter	With Respect to	Min	Typ	Max	Unit
VDD	ACOM	-0.3		6.5	V
CLOCK, SLEEP	ACOM	-0.3		$A_{VDD} + 0.3$	V
Digital Inputs	ACOM	-0.3		$A_{VDD} + 0.3$	V
I _{OUTA} , I _{OUTB}	ACOM	-0.3		1.8	V
COMP1	ACOM	-0.3		$A_{VDD} + 0.3$	V
COMP2	ACOM	-0.3		1.8	V
FS ADJ	ACOM	-0.3		1.8	V
REFIO	ACOM	-0.3		$A_{VDD} + 0.3$	V
REFLO	ACOM	-0.3		0.3	V
T _J	Maximum Operating Junction Temperature			125	°C
T _{STG}	Storage Temperature Range	-65		150	°C
T _L	Lead Temperature (Soldering, 10 sec)			300	°C

(1) Stresses above those listed under absolute maximum ratings may cause permanent damage to the device. This is a stress rating only. The functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum ratings for extended periods may affect the reliability of the device.

ESD, Electrostatic Discharge Protection

Symbol	Parameter	Condition	Minimum Level	Unit
HBM	Human Body Model ESD	ANSI/ESDA/JEDEC JS-001 ⁽¹⁾	±1000	V
CDM	Charged Device Model ESD	ANSI/ESDA/JEDEC JS-002 ⁽²⁾	±500	V

(1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

(2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

Thermal Information

Package Type	θ_{JA}	θ_{JC}	Unit
TSSOP28	97.9	14.0	°C/W

Electrical Characteristics

DC Specifications

All test conditions: T_{MIN} to T_{MAX} , $AVDD = +5\text{ V}$, $I_{OUTFS} = 20\text{ mA}$, unless otherwise noted.

Symbol	Parameter	Min	Typ	Max	Unit
	Resolution	10			Bits
	Monotonicity	Guaranteed over specified temperature range.			
	Operating Range	-40		+85	°C
DC Accuracy ⁽¹⁾					
INL	Integral Linearity Error	-2.3	±1/2	-2.3	LSB
DNL	Differential Nonlinearity	-2	±1/4	2	LSB
Analog Output					
	Offset Error	-0.6		0.6	% of FSR
	Gain Error (Without Internal Reference)		±2		% of FSR
	Gain Error (With Internal Reference)	-15	±2	+15	% of FSR
	Full-Scale Output Current ⁽²⁾	2		20	mA
	Output Compliance Range (Single End)	0.2		0.8	V
	Output Resistance		100		kΩ
	Output Capacitance		5		pF
Reference Output					
	Reference Voltage	0.89	1.075	1.26	V
Reference Input					
	Input Compliance Range			1.25	V
	Reference Input Resistance		1		M
Temperature Coefficients					
	Offset Drift		10		ppm of FSR/°C
	Gain Drift (With Internal Reference)		±50		ppm of FSR/°C
Power Supply					
	Supply Voltages of AVDD ⁽⁵⁾	2.7	5	5.5	V
I_{AVDD}	Analog Supply Current		21	30	mA
	Power Dissipation (5 V, $I_{OUTFS} = 20\text{ mA}$)		110		mW

(1) Measured at I_{OUTA} , driving a virtual ground.

(2) The nominal full-scale current, I_{OUTFS} , is 32 x the I_{REF} current. Design valid.

(3) Use an external buffer amplifier to drive any external load.

(4) The reference bandwidth is a function of the external cap at the COMP1 pin.

(5) For operation below 3 V, it is recommended that the output current be reduced to 12 mA or less to maintain optimum performance.

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Dynamic Specifications (Specifications subject to change without notice.)

 All test conditions: T_{MIN} to T_{MAX} , $AVDD = +5\text{ V}$, $I_{OUTFS} = 20\text{ mA}$, Differential Output, 30- Ω Terminated, unless otherwise noted.

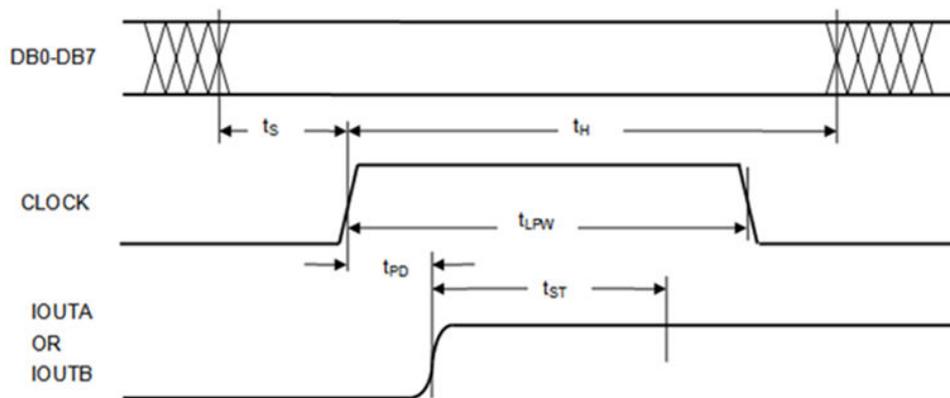
Symbol	Parameter	Conditions	Min	Typ	Max	Unit
Dynamic Performance						
f_{CLOCK}	Maximum Output Update Rate			125		MSPS
t_{ST}	Output Settling Time (to 0.1%) ⁽¹⁾			35		ns
t_{PD}	Output Propagation Delay			1		ns
	Glitch Impulse			5		pV-s
	Output Rise Time (10% to 90%) ⁽¹⁾			2.5		ns
	Output Fall Time (10% to 90%) ⁽¹⁾			2.5		ns
	Output Noise ($I_{OUTFS} = 20\text{ mA}$)			50		pA/ $\sqrt{\text{Hz}}$
	Output Noise ($I_{OUTFS} = 2\text{ mA}$)			30		pA/ $\sqrt{\text{Hz}}$
AC Linearity to Nyquist						
	Total Harmonic Distortion	$f_{CLOCK} = 100\text{ MSPS}$, $f_{OUT} = 1\text{ MHz}$		-62		dBc
	Spurious-Free Dynamic Range to Nyquist	$f_{CLOCK} = 100\text{ MSPS}$, $f_{OUT} = 1\text{ MHz}$		64		dBc
	Signal Noise Ratio	$f_{CLOCK} = 100\text{ MSPS}$, $f_{OUT} = 1\text{ MHz}$		52		dBc

 (1) Measured single ended into a 50- Ω load.

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Digital Specifications (Specifications subject to change without notice.)

 All test conditions: T_{MIN} to T_{MAX} , $AVDD = +5\text{ V}$, $I_{OUTFS} = 20\text{ mA}$, unless otherwise noted.

Symbol	Parameter	Min	Typ	Max	Unit
Digital Inputs					
	Logic "1" Voltage @ $AVDD = +5\text{ V}$	4	5		V
	Logic "1" Voltage @ $AVDD = +3\text{ V}$	2.4	3		V
	Logic "0" Voltage @ $AVDD = +5\text{ V}$		0	0.6	V
	Logic "0" Voltage @ $AVDD = +3\text{ V}$		0	0.6	V
	Logic "1" Current		1		μA
	Logic "0" Current		1		μA
	Input Capacitance		5		pF
t_s	Input Setup Time		2		ns
t_H	Input Hold Time		1.5		ns
t_{LPW}	Latch Pulsewidth		3.5		ns


3PD5651E
Figure 1. Timing Diagram

Definitions of Specifications

Linearity Error (Also Called Integral Nonlinearity or INL)

The linearity error is defined as the maximum deviation of the actual analog output from the ideal output, determined by a straight line drawn from zero to full scale.

Differential Nonlinearity (or DNL)

DNL is the measure of the variation in analog value, normalized to full scale, associated with a 1 LSB change in digital input code.

Monotonicity

A D/A converter is monotonic if the output either increases or remains constant as the digital input increases.

Offset Error

The deviation of the output current from the ideal of zero is called offset error. For I_{OUTA} , a 0-mA output is expected when the inputs are all 0 s. For I_{OUTB} , a 0-mA output is expected when all inputs are set to 1 s.

Gain Error (The Difference Between the Actual and Ideal Output Span)

The actual span is determined by the output when all inputs are set to 1 s minus the output when all inputs are set to 0 s.

Output Compliance Range

The range of the allowable voltage at the output of a current-output DAC. Operation beyond the maximum compliance limits may cause either output stage saturation or breakdown resulting in nonlinear performance.

Temperature Drift

The temperature drift is specified as the maximum change from the ambient (+25°C) value to the value at either T_{MIN} or T_{MAX} . For the offset and gain drift, the drift is reported in ppm of full-scale range (FSR) per °C. For the reference drift, the drift is reported in ppm per °C.

Power Supply Rejection

The maximum changes in the full-scale output as the supplies are varied from nominal to minimum and maximum specified voltages.

Settling Time

The time required for the output to reach and remain within a specified error band about its final value, measured from the start of the output transition.

Glitch Impulse

The asymmetrical switching times in a DAC give rise to undesired output transients that are quantified by a glitch impulse. It is specified as the net area of the glitch in pV-s.

Spurious-Free Dynamic Range

The difference, in dB, between the RMS amplitude of the output signal and the peak spurious signal over the specified bandwidth.

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Signal-to-Noise and Distortion (S/N+D, SINAD) Ratio

SINAD is the ratio of the RMS value of the measured output signal to the RMS sum of all other spectral components below the Nyquist frequency, including harmonics but excluding DC. The value for SINAD is expressed in decibels.

Total Harmonic Distortion

THD is the ratio of the RMS sum of the first six harmonic components to the RMS value of the measured output signal. It is expressed as a percentage or in decibels.

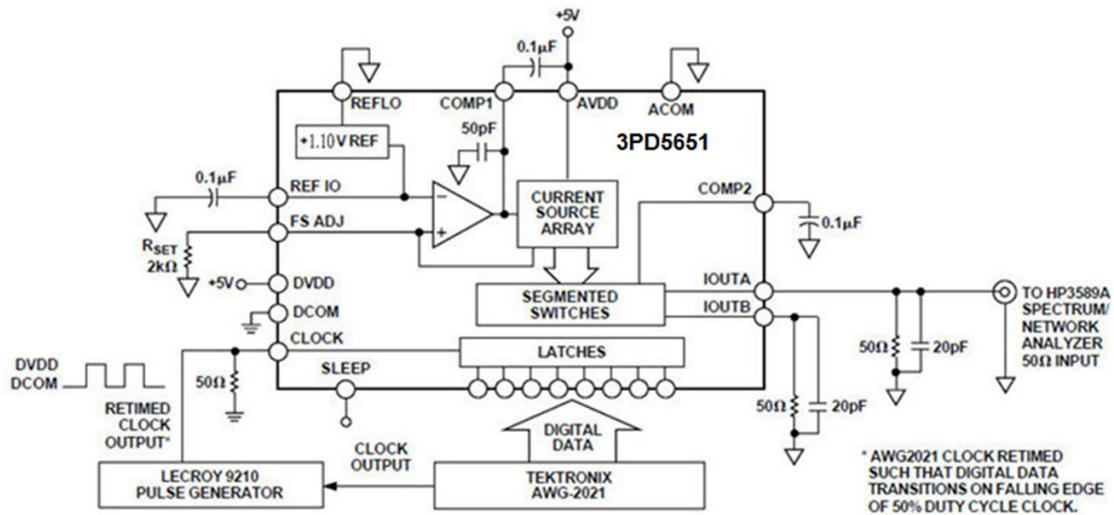


Figure 2. Basic AC Characterization Test Setup

Detailed Description

Overview

The 3PD5651E consists of a large PMOS current source array capable of providing a total current of up to 20 mA. The array is divided into 32 equal currents that make up the five most significant bits (MSBs). The remaining 3 LSBs are also implemented with equally weighted current sources whose sum total equals 7/8 of an MSB current source. Implementing the upper and lower bits with current sources helps maintain the high output impedance of DAC (i.e. > 100 kΩ). All of these current sources are switched to one or the other of the two output nodes (i.e., I_{OUTA} or I_{OUTB}) via PMOS differential current switches. The switches are based on a new architecture that drastically improves distortion performance.

The analog and digital sections of the 3PD5651E have separate power supply inputs (i.e., AVDD) that can operate independently over a 2.7-V to 5.5-V range. The digital section, which is capable of operating up to a 125MSPS clock rate, consists of edge-triggered latches and segment decoding logic circuitry. The analog section includes the PMOS current sources, the associated differential switches, a 1.10-V bandgap voltage reference, and a reference control amplifier.

The full-scale output current is regulated by the reference control amplifier and can be set from 2 mA to 20 mA via an external resistor, R_{SET}. The external resistor, in combination with both the reference control amplifier and the voltage reference V_{REFIO}, sets the reference current I_{REF}, which is mirrored over to the segmented current sources with the proper scaling factor. The full-scale current, I_{OUTFS}, is thirty-two times the value of I_{REF}.

Functional Block Diagram

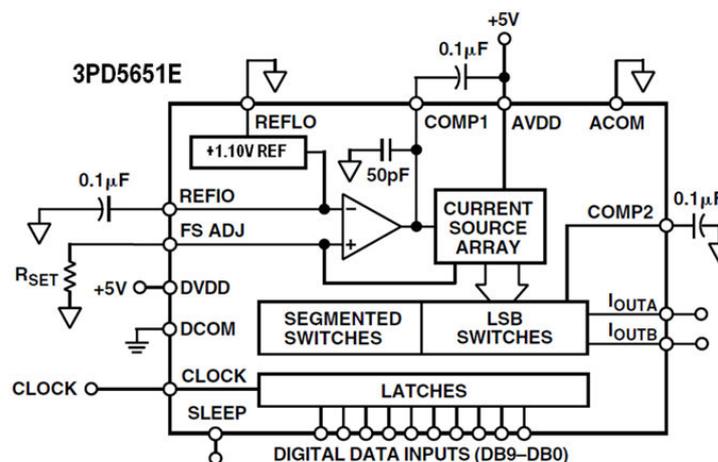


Figure 3. Functional Block Diagram

Feature Description

DAC Transfer Function

The 3PD5651E provides complementary current outputs, I_{OUTA} and I_{OUTB}. I_{OUTA} provides a near full-scale current output, I_{OUTFS}, when all bits are high (i.e., DAC CODE = 255), while I_{OUTB}, the complementary output, provides no current. The current output appearing at I_{OUTA} and I_{OUTB} are a function of both the input code and I_{OUTFS} and can be expressed as:

$$I_{OUTA} = \frac{DAC\ CODE}{256} \times I_{OUTFS} \quad (1)$$

$$I_{OUTB} = \frac{255 - DAC\ CODE}{256} \times I_{OUTFS} \quad (2)$$

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Where DAC CODE = 0 to 255 (i.e., Decimal Representation).

As previously mentioned, I_{OUTFS} is a function of the reference current I_{REF} , which is nominally set by a reference voltage V_{REFIO} and the external resistor R_{SET} . It can be expressed as:

$$I_{OUTFS} = 32 \times I_{REF} \quad (3)$$

Where $I_{REF} = \frac{V_{REFIO}}{R_{SET}}$

$$V_{OUTA} = I_{OUTA} \times R_{LOAD} \quad (4)$$

$$V_{OUTB} = I_{OUTB} \times R_{LOAD} \quad (5)$$

Note that the full-scale value of V_{OUTA} and V_{OUTB} should not exceed the specified output compliance range to maintain specified distortion and linearity performance.

The differential voltage, V_{DIFF} , appearing across I_{OUTA} and I_{OUTB} is:

$$V_{DIFF} = (I_{OUTA} - I_{OUTB}) \times R_{LOAD} \quad (6)$$

Substituting the values of I_{OUTA} , I_{OUTB} , and I_{REF} ; V_{DIFF} can be expressed as:

$$V_{DIFF} = \frac{2 \times \text{DAC CODE} - 255}{256} \times 32 \times \frac{R_{LOAD}}{R_{SET}} \times V_{REFIO} \quad (7)$$

Voltage Reference and Control Amplifier

The 3PD5651E contains an internal 1.10-V bandgap reference that can be easily disabled and overridden by an external reference. REFIO serves as either an *input* or *output* depending on whether an internal or an external reference is selected. If REFLO is tied to ACOM, as shown in Figure 4, the internal reference is activated and REFIO provides a 1.10-V output. In this case, the internal reference must be compensated externally with a ceramic chip capacitor of 0.1 mF or greater from REFIO to REFLO. Note that REFIO is not designed to drive any external load. It should be buffered with an external amplifier having an input bias current less than 100 nA if any additional loading is required.

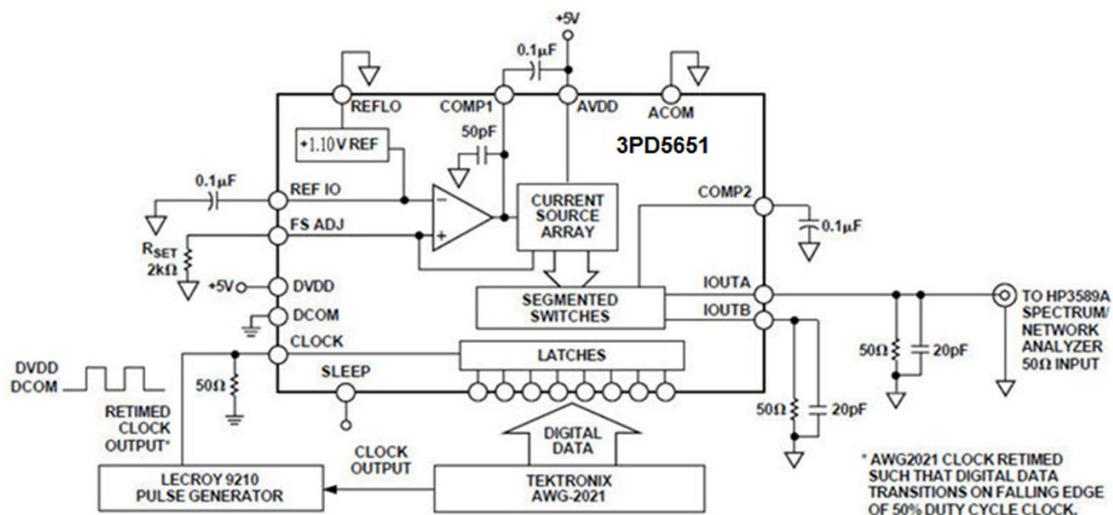


Figure 4. Internal Reference Configuration

The internal reference can be disabled by connecting REFLO to AVDD. In this case, an external reference may then be applied to REFIO as shown in Figure 5. The external reference may provide either a fixed reference voltage to enhance accuracy and drift performance or a varying reference voltage for gain control. Note that the 0.1-mF compensation capacitor is not required since the internal reference is disabled, and the high input impedance (i.e., 1 MΩ) of REFIO minimizes any loading of the external reference.

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The small signal bandwidth of the reference control amplifier is approximately 1.8 MHz and can be reduced by connecting an external capacitor between COMP1 and AVDD. The output of the control amplifier, COMP1, is internally compensated via a 50-pF capacitor that limits the control amplifier small-signal bandwidth and reduces its output impedance. Any additional external capacitance further limits the bandwidth and acts as a filter to reduce the noise contribution from the reference amplifier. If I_{REF} is fixed for an application, a 0.1-mF ceramic chip capacitor is recommended.

I_{REF} can be varied for a fixed R_{SET} by disabling the internal reference and varying the common-mode voltage over its compliance range of 1.25 V to 0.10 V. REFIO can be driven by a single-supply amplifier or DAC, and thus allowing I_{REF} to be varied for a fixed R_{SET} . Since the input impedance of REFIO is approximately 1 M Ω , a simple R-2-R ladder DAC configured in the voltage mode topology may be used to control the gain. Note that another 3PD5651E could also be used as the gain control DAC since it can also provide a programmable unipolar output up to 1.2 V.

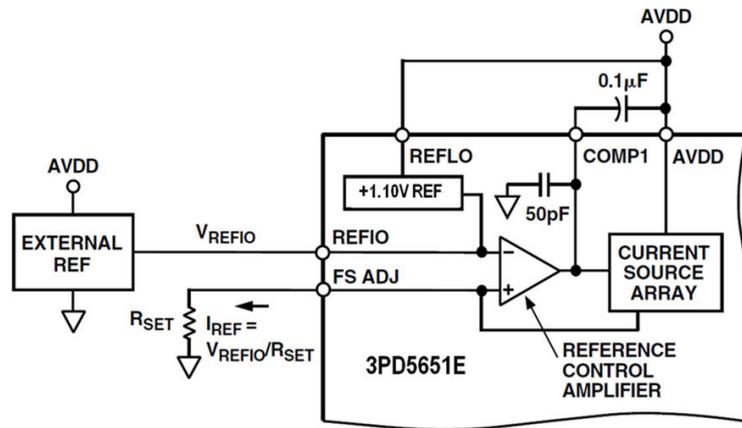


Figure 5. External Reference Configuration

Application and Implementation

Note

Information in the following application sections is not part of the 3PEAK's component specification and 3PEAK does not warrant its accuracy or completeness. 3PEAK's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

Application Information

Analog Outputs and Output Configurations

The 3PD5651E produces two complementary current outputs, I_{OUTA} and I_{OUTB} , which may be converted into complementary single-ended voltage outputs, V_{OUTA} and V_{OUTB} , via a load resistor, R_{LOAD} , as described in the [DAC Transfer Function](#) section. [Figure 6](#) shows the 3PD5651E configured to provide a positive unipolar output range of approximately 0 V to +0.5 V for a double terminated 50- Ω cable for a nominal full-scale current, I_{OUTFS} , of 20 mA. In this case, R_{LOAD} represents the equivalent load resistance seen by I_{OUTA} or I_{OUTB} and is equal to 25 Ω . The unused output (I_{OUTA} or I_{OUTB}) can be connected to ACOM directly or via a matching R_{LOAD} . Different values of I_{OUTFS} and R_{LOAD} can be selected as long as the positive compliance range is adhered to.

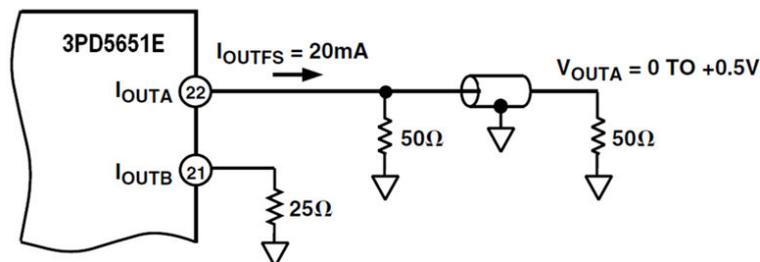


Figure 6. 0-V to +0.5-V Unbuffered Voltage Output

Alternatively, an amplifier could be configured as an I-V converter, and thus converting I_{OUTA} or I_{OUTB} into a negative unipolar voltage. [Figure 7](#) shows a buffered single-ended output configuration in which the op amp, U1, performs an I-V conversion on the 3PD5651E output current. U1 provides a negative unipolar output voltage and its full-scale output voltage is simply the product of R_{FB} and I_{OUTFS} . The full-scale output should be set within voltage output swing capabilities of U1 by scaling I_{OUTFS} and/or R_{FB} . An improvement in AC distortion performance may result with a reduced I_{OUTFS} , since the signal current U1 is required to sink and is subsequently reduced. Note that the AC distortion performance of this circuit at higher DAC update rates may be limited by the slewing capabilities of U1.

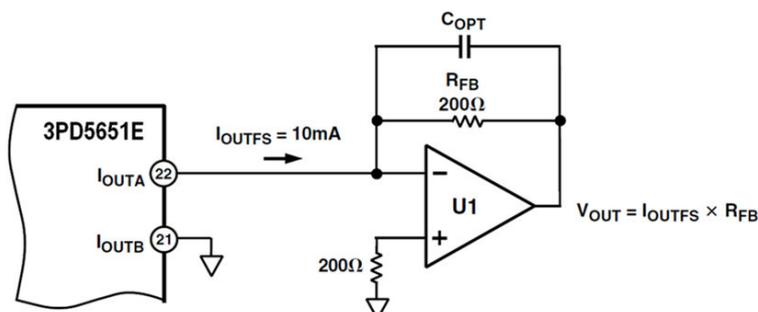


Figure 7. Unipolar Buffered Voltage Output

I_{OUTA} and I_{OUTB} also have a negative and positive voltage compliance range that must be adhered to in order to achieve optimum performance. The positive output compliance range is slightly dependent on the full-scale output current, I_{OUTFS} . It

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degrades slightly from its nominal 1.25 V for an $I_{OUTFS} = 20$ mA to 1.00 V for an $I_{OUTFS} = 2$ mA. Applications requiring the output of the 3PD5651E (i.e., V_{OUTA} and/or V_{OUTB}) to extend up to its output compliance range should size R_{LOAD} accordingly. Operation beyond this compliance range adversely affects the linearity of the 3PD5651E. The differential voltage, V_{DIFF} , existing between V_{OUTA} and V_{OUTB} may also be converted to a single-ended voltage via a transformer or differential amplifier configuration.

Digital Inputs

The digital input of the 3PD5651E consists of eight data input pins and a clock input pin. The 10-bit parallel data inputs follow standard positive binary coding where DB9 is the most significant bit (MSB) and DB0 is the least significant bit (LSB). The digital interface is implemented using an edge-triggered master slave latch. The output of the 3PD5651E is updated following the rising edge as shown in Figure 1 and is designed to support a clock rate as high as 125 MSPS. The clock can be operated at any duty cycle that meets the specified latch pulse-width. The setup-and-hold times can also be varied within the clock cycle as long as the specified minimum times are met; although the location of these transition edges may affect the digital feed-through and distortion performance.

The digital inputs are CMOS compatible with logic thresholds, $V_{THRESHOLD}$, set to approximately half the digital positive supply.

Figure 8 shows the equivalent digital input circuit for the data and clock inputs. The sleep mode input is similar, except that it contains an active pull-down circuit, thus ensuring that the 3PD5651E remains enabled if this input is left disconnected. The internal digital circuitry of the 3PD5651E is capable of operating over a digital supply range of 2.7 V to 5.5 V. As a result, the digital inputs can also accommodate TTL levels when V_{DD} is set to accommodate the maximum high level voltage, $V_{OH(MAX)}$, of the TTL drivers. A V_{DD} of 3 V to 3.3 V typically ensures upper compatibility of most TTL logic families.

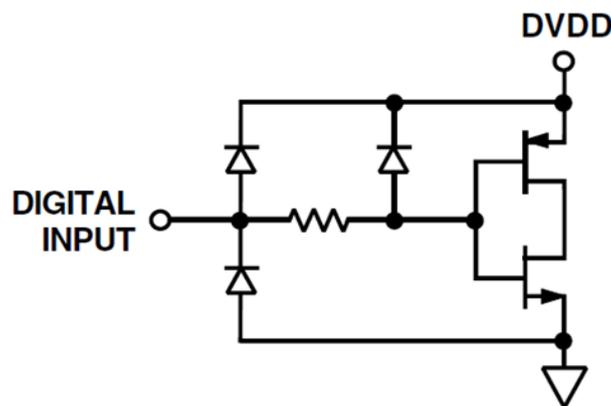


Figure 8. Equivalent Digital Input

Since the 3PD5651E is capable of being updated up to 125 MSPS, the quality of the clock and data input signals are important in achieving the optimum performance. The drivers of the digital data interface circuitry should be specified to meet the minimum setup-and-hold times of the 3PD5651E as well as its required min/max input logic level thresholds. Typically, the selection of the slowest logic family that satisfies the above conditions results in the lowest data feed-through and noise. Digital signal paths should be kept short and run lengths matched to avoid the propagation delay mismatch. The insertion of a low value resistor network (i.e., 20 Ω to 100 Ω) between the digital inputs and driver outputs of the 3PD5651E may be helpful in reducing any overshooting and ringing at the digital inputs that contribute to data feed-through. For longer run lengths and high data update rates, strip line techniques with proper termination resistors should be considered to maintain "clean" digital inputs. Also, operating the 3PD5651E with reduced logic swings and a corresponding digital supply also reduces the data feed-through. The external clock driver circuitry should provide the 3PD5651E with a low jitter clock input meeting the min/max logic levels while providing fast edges. Fast clock edges help minimize any jitter that manifests itself as phase noise on a reconstructed waveform. However, the clock input could also be driven by via a sine wave, which is centered around the digital threshold (i.e., $V_{DD}/2$), and meets the min/max logic threshold. This may result in a slight degradation in the phase noise, which becomes more noticeable at higher sampling rates and output frequencies. Note that

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at higher sampling rates the 20% tolerance of the digital logic threshold should be considered since it affects the effective clock duty cycle and subsequently cut into the required data setup-and-hold times.

Sleep Mode Operation

The 3PD5651E has a power-down function that turns off the output current and reduces the supply current to less than 8.5 mA over the specified supply range of 2.7 V to 5.5 V and the temperature range. This mode can be activated by applying a logic level “1” to the SLEEP pin. This digital input also contains an active pull-down circuit that ensures the 3PD5651E remains enabled if this input is left disconnected. The SLEEP input with active pull-down requires a drive current of <40 mA.

The power-up and power-down characteristics of the 3PD5651E are dependent on the value of the compensation capacitor connected to COMP2 (Pin 23). With a nominal value of 0.1 mF, the 3PD5651E takes less than 5 ms to power down and approximately 3.25 ms to power back up.

Power Dissipation

The power dissipation, P_D , of the 3PD5651E is dependent on several factors, including:

1. AVDD, the power supply voltages;
2. I_{OUTFS} , the full-scale current output;
3. f_{CLOCK} , the update rate;
4. the reconstructed digital input waveform.

Power and Grounding Considerations

In systems seeking to simultaneously achieve high speed and high performance, the implementation and construction of the printed circuit board design is often as important as the circuit design. Proper RF techniques must be used in the selection placement and routing and supply bypassing and grounding of the device. The evaluation board for the 3PD5651E, which uses a four layer PCB, serves as a good example for the above mentioned considerations. The evaluation board provides an illustration of the recommended printed circuit board ground, power and signal plane layouts.

The proper grounding and decoupling should be a primary objective in any high speed system. The 3PD5651E features the separate analog and digital supply and ground pins to optimize the management of the analog and digital ground currents in a system. In general, AVDD, the analog supply, should be decoupled to ACOM, the analog common, as close to the chip as physically possible.

For those applications requiring a single +5-V or +3-V supply for both the analog and digital supply, a clean analog supply may be generated using the circuit shown in Figure 9. The circuit consists of a differential LC filter with separate power supply and return lines. Lower noise can be attained using low ESR type electrolytic and tantalum capacitors.

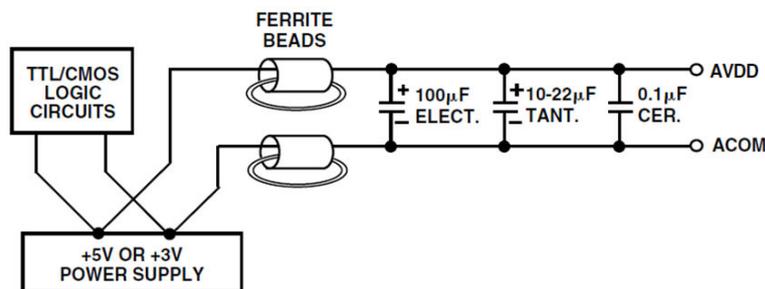


Figure 9. Differential LC Filter for Single +5-V or +3-V Applications

Maintaining low noise on power supplies and ground is critical to obtaining optimum results from the 3PD5651E. If properly implemented, ground planes can perform a host of functions on high speed circuit boards: bypassing, shielding, current transport, etc. In the mixed signal design, the analog and digital portions of the board should be distinct from each other, with the analog ground plane confined to the areas covering the analog signal traces, and the digital ground plane confined to areas covering the digital interconnects.

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All analog ground pins of the DAC, reference and other analog components, should be tied directly to the analog ground plane. The two ground planes should be connected by a path 1/8 to 1/4 inch wide underneath or within 1/2 inch of the DAC to maintain optimum performance. Care should be taken to ensure that the ground plane is uninterrupted over crucial signal paths. On the digital side, this includes the digital input lines running to the DAC as well as any clock signals. On the analog side, this includes the DAC output signal, reference signal, and the supply feeders.

The use of wide runs or planes in the routing of power lines is also recommended. This serves the dual role of providing a low series impedance power supply to the part, as well as providing some “free” capacitive decoupling to the appropriate ground plane. It is essential that care be taken in the layout of signal and power ground interconnects to avoid inducing extraneous voltage drops in the signal ground paths. It is recommended that all connections should be short, direct, and as physically close to the package as possible in order to minimize the sharing of conduction paths between different currents. When runs exceed an inch in length, strip line techniques with proper termination resistor should be considered. The necessity and value of this resistor is dependent upon the logic family used.

For applications requiring the optimum dynamic performance and/or a bipolar output swing, a differential output configuration is suggested. A differential output configuration may consist of either an RF transformer or a differential op amp configuration. The transformer configuration is well suited for AC coupling applications. It provides the optimum high-frequency performance due to its excellent rejection of common-mode distortion (i.e., even-order harmonics) and noise over a wide frequency range. It also provides electrical isolation and the ability to deliver twice the power to the load (i.e., assuming no source termination). The differential op amp configuration is suitable for applications requiring DC coupling, a bipolar output, signal gain, and/or level shifting.

Figure 10 shows the 3PD5651E in a typical transformer coupled output configuration. The center-tap on the primary side of the transformer must be connected to ACOM to provide the necessary DC current path for both I_{OUTA} and I_{OUTB} . The complementary voltages appearing at I_{OUTA} and I_{OUTB} (i.e., V_{OUTA} and V_{OUTB}) swing symmetrically around ACOM and should be maintained within the specified output compliance range of the 3PD5651E. A differential resistor, R_{DIFF} , may be inserted in applications in which the output of the transformer is connected to the load, R_{LOAD} , via a passive reconstruction filter or cable. R_{DIFF} is determined by the transformer’s impedance ratio and provides the proper source termination. Note that approximately half the signal power is dissipated across R_{DIFF} .

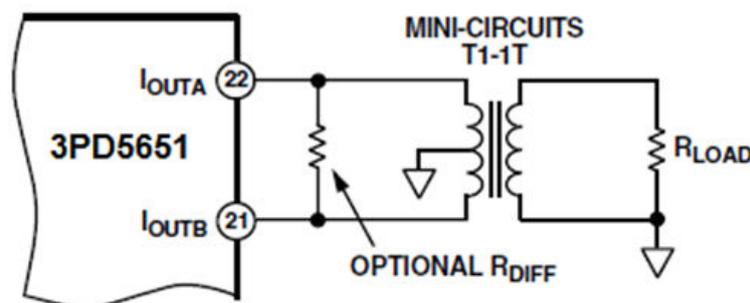


Figure 10. Differential Output Using a Transformer

An op amp can also be used to perform a differential to the single-ended conversion as shown in Figure 11. The 3PD5651E is configured with two equal load resistors, R_{LOAD} , of 25 Ω . The differential voltage developed across I_{OUTA} and I_{OUTB} is converted to a single-ended signal via the differential op amp configuration. An optional capacitor can be installed across I_{OUTA} and I_{OUTB} forming a real pole in a low-pass filter. The addition of this capacitor also enhances the distortion performance of the operational amplifier by preventing the DACs high slewing output from overloading the input of the amplifier.

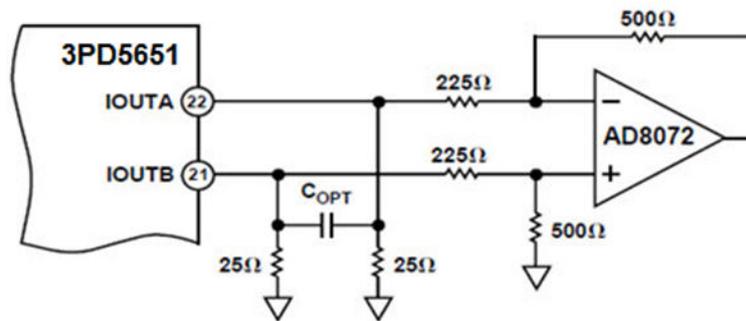


Figure 11. DV Differential Coupling Using an Op Amp

The common-mode rejection of this configuration is typically determined by the resistor matching. In this circuit, the differential circuit is configured to provide some additional signal gain. The op amp must operate off a dual supply since its output is approximately ± 1.0 V. A high-speed amplifier capable of preserving the differential performance of the 3PD5651E while meeting other system level objectives (i.e., cost and power) should be selected. The differential gain of the amplifier, its gain setting resistor values, and full-scale output swing capabilities should all be considered when optimizing this circuit.

The differential circuit shown in [Figure 12](#) provides the necessary level-shifting required in a single supply system. In this case, AVDD, which is the positive analog supply for both the 3PD5651E and the op amp, is also used to level-shift the differential output of the 3PD5651E to the mid-supply (i.e., AVDD/2).

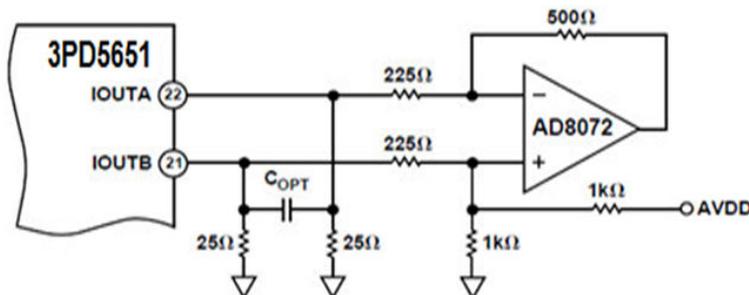
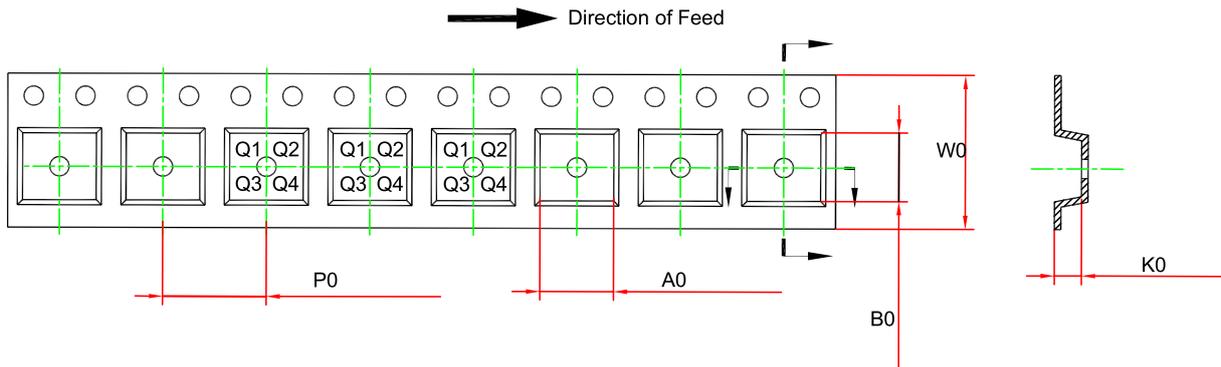
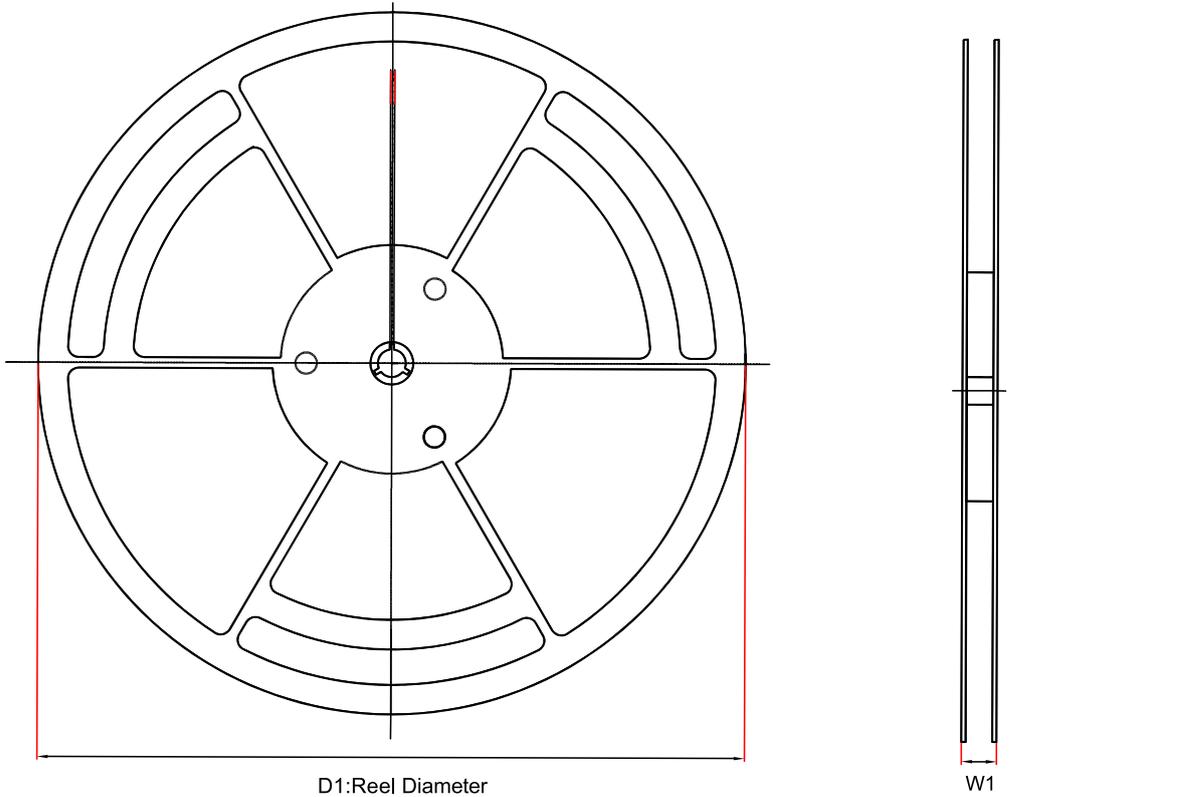
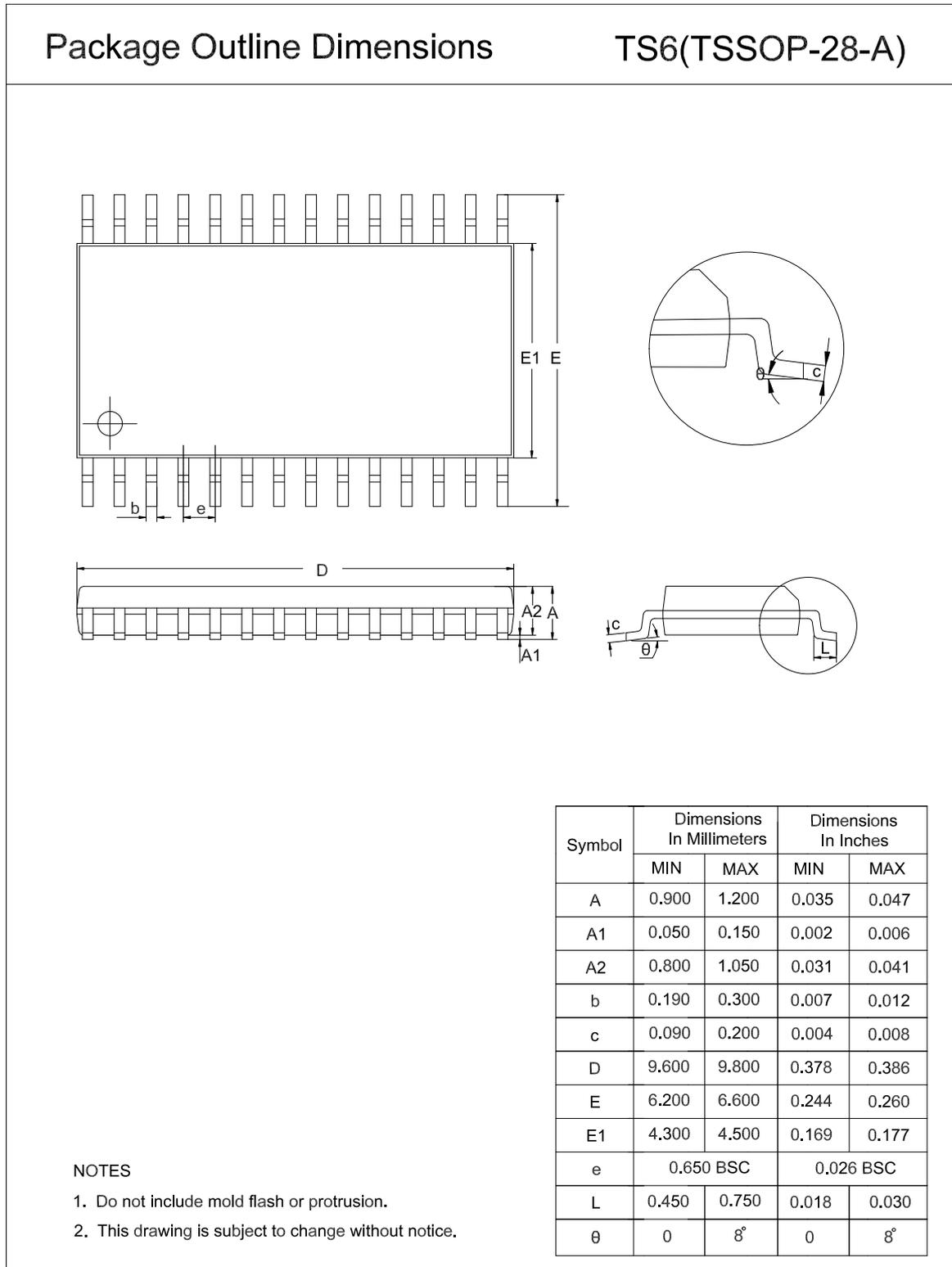


Figure 12. Single-Supply DC Differential Coupled Circuit

Tape and Reel Information


Order Number	Package	D1 (mm)	W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P0 (mm)	W0 (mm)	Pin1 Quadrant
3PD5651E	TSSOP28	330	21.6	6.8	10.15	1.6	8	16	Q1

Package Outline Dimensions
TSSOP28


Order Information

Order Number	Operating Temperature Range	Package	Marking Information	MSL	Transport Media, Quantity	Eco Plan
3PD5651E	-40 to 85°C	TSSOP28	3PD5651E	3	Tape and Reel, 2500	Green

Green: 3PEAK defines "Green" to mean RoHS compatible and free of halogen substances.

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